



Contribution ID: 61

Type: **Invited**

Neutron depth profiling, present day applications in Lithium ion batteries

Tuesday 19 July 2016 15:10 (20 minutes)

First used to measure Boron impurities in silicon wafers, neutron depth profiling has recently gained renewed attention as a non-destructive method for studying of lithium concentration variations along the electrode depth in lithium ion batteries. The presenter will demonstrate application to the high power density and environmentally benign cathode material LiFePO₄. The results obtained, both in operando as well as ex-situ, provide important insight for electrode design and inspire the development of novel computational methods.

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Session Classification: Session V: Batteries 2 (Chair: Helmut Ehrenberg)

Track Classification: Energy storage & transformation